

Supporting Information

Synthesis and Stress Relaxation of

ZnO/Al Doped ZnO Core-Shell Nanowires

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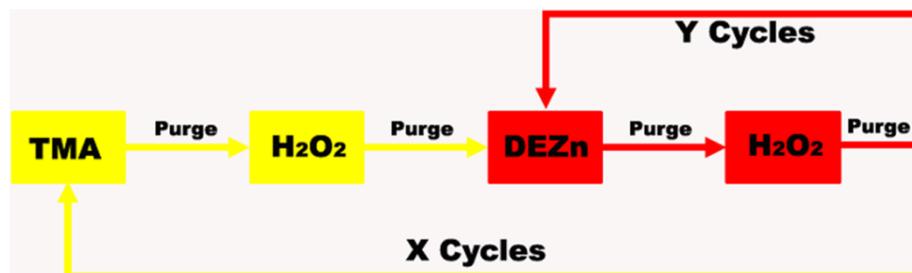


Figure S1. Schematic diagram of deposition process. X:Y was fixed at 1:20 in this work.

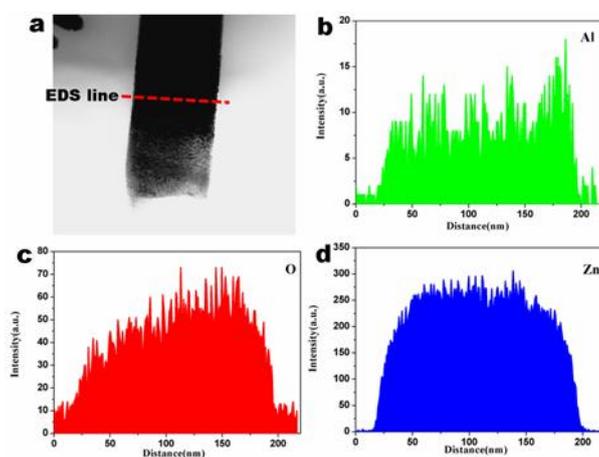


Figure S2. The distribution profiles of the element Zn, O and Al; Inset shows the location for the EDX line scan.

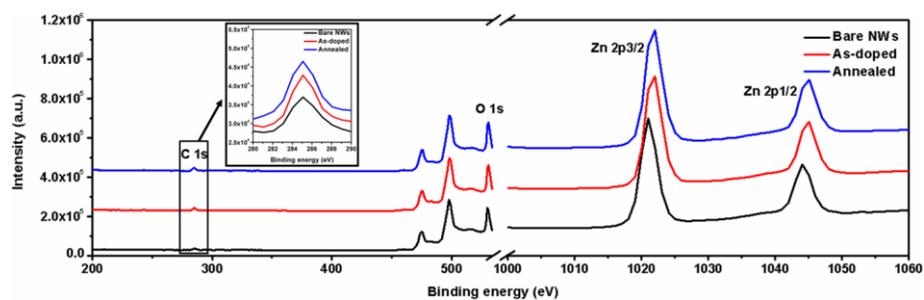


Figure S3. XPS curves after calibration by C1s at 284.6eV.